

Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination
	09/874,499	KIPP ET AL.
Examiner	Art Unit	
Simon J. Oh	1618	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
424	400 450 484	5/12/03	S.D.
264	4, 4.1, 5		